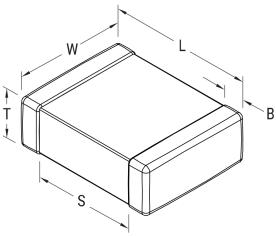


C0603C622M4HACTU

Aliases (C0603C622M4HAC7867)

SMD Comm X8R HT150C, Ceramic, 6200 pF, 20%, 16 VDC, X8R, SMD, MLCC, High Temperature, Ultra-Stable, 0603



Click here for the 3D model.

| Dimensions | |
|------------|------------------|
| Chip Size | 0603 |
| L | 1.6mm +/-0.15mm |
| W | 0.8mm +/-0.15mm |
| Т | 0.8mm +/-0.07mm |
| S | 0.7mm MIN |
| В | 0.35mm +/-0.15mm |

| Packaging Specifications | |
|--------------------------|------------------------|
| Packaging | T&R, 180mm, Paper Tape |
| Packaging Quantity | 4000 |

| General Information | |
|---------------------|---|
| Series | SMD Comm X8R HT150C |
| Style | SMD Chip |
| Description | SMD, MLCC, High Temperature, Ultra-Stable |
| Features | High Temperature, Ultra-Stable |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| AEC-Q200 | No |
| Component Weight | 4.8 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Specifications | |
|--|--|
| Capacitance | 6200 pF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Capacitance Tolerance | 20% |
| Voltage DC | 16 VDC |
| Dielectric Withstanding Voltage | 40 VDC |
| Temperature Range | -55/+150°C |
| Temperature Coefficient | X8R |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 15%, 1kHz 1.0Vrms |
| Dissipation Factor | 2.5% 1 kHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour: Referee Time is 1000 Hours |
| Insulation Resistance | 100 GOhms |

Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and we specifically disclaim - any warranty concerning suitability for a specific customer application or use. This Information is intended for use only by customers who have the requisite experience and capability to determine the correct products for their application. Any technical advice inferred from this Information or otherwise provided by us with reference to the use of our products is given gratis, and we assume no obligation or liability for the advice given or results obtained.